

**Notice of References Cited**

Application/Control No.

10/821,608

Applicant(s)/Patent Under  
Reexamination  
AGRAWAL ET AL.

Examiner

BACKHEAN TIV

Art Unit

2451

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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